# Title of your sample series

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## Sample declaration:

|  |  |  |  |  |
| --- | --- | --- | --- | --- |
| **Sample** | **Material** | **amount** | **unit** | **Nanoparticle** |
| Sample Series 1 | Polymer Full name (chem Formula) | 10-50 | µg | no |
|  | ethylene glycol | 0-20 | µg | no |
|  | PEDOT:PSS | 5 | µg | no |
|  | PC60BM | 5 | µg | embedded in film |
|  |  |  |  |  |
|  |  |  |  |  |
|  |  |  |  |  |

## Desired characterization:

Please specify the length scale of features you would like to detect (object sizes and separations or atomic spacings of interest). And describe what you already know about the surface/inner morphology. If you have AFM or SEM images, insert these.

If you have experience with the method and already know which measurements you want to have taken, please also indicate which incident angles, how many positions on sample, knowledge on beam damage. Do you require double exposure to remove horizontal detector gaps (requires 2 measurements and reduces the total number of samples you can measure).

If you have no experience with experiments we will help you.

## Aim & Importance of the experiment

Please describe what you want to achieve with the measurements and why this is interesting for your particular system.